

A Count Rate-Dependent Method for Spectral Distortion Correction in Photon Counting CT

Jannis Dickmann^{a,b,c}, Joscha Maier^{a,d}, Stefan Sawall^{a,d}, Thomas Thüring^e,
Spyridon Gkoumas^e, Christian Brönnimann^e, and Marc Kachelrieß^{a,d}

^aGerman Cancer Research Center (DKFZ), Heidelberg, Germany

^bKTH Royal Institute of Technology, Stockholm, Sweden

^cTechnical University of Darmstadt, Germany

^dUniversity of Heidelberg, Germany

^eDectris Ltd., Baden, Switzerland

www.dkfz.de/ct



DEUTSCHES
KREBSFORSCHUNGZENTRUM
IN DER HELMHOLTZ-GEMEINSCHAFT

Aim

- Material decomposition of **spectral CT** data into contributions of iodine and water
- Table-top setup with a prototype **photon-counting detector (PCD)**
- Calibration of **spectral response** to account for...
 - Spectral distortions: charge sharing, K-escape
 - Count rate-dependent distortions: pulse pileup

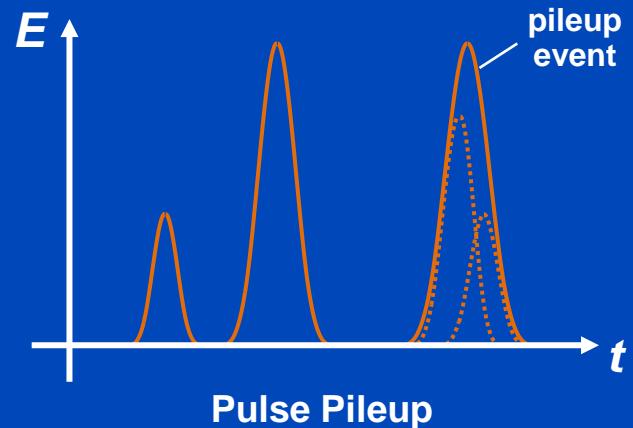
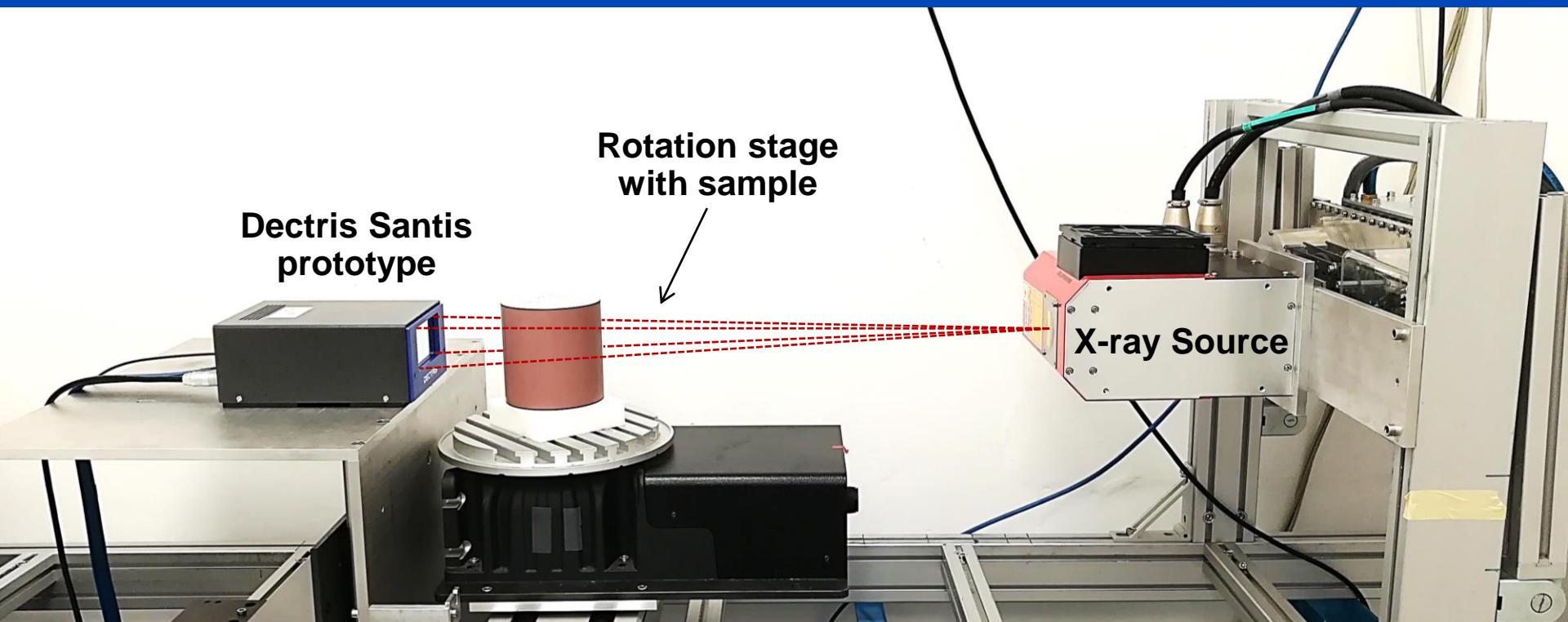


Table-Top Photon Counting CT



Pixel

512 x 256

Pixel size

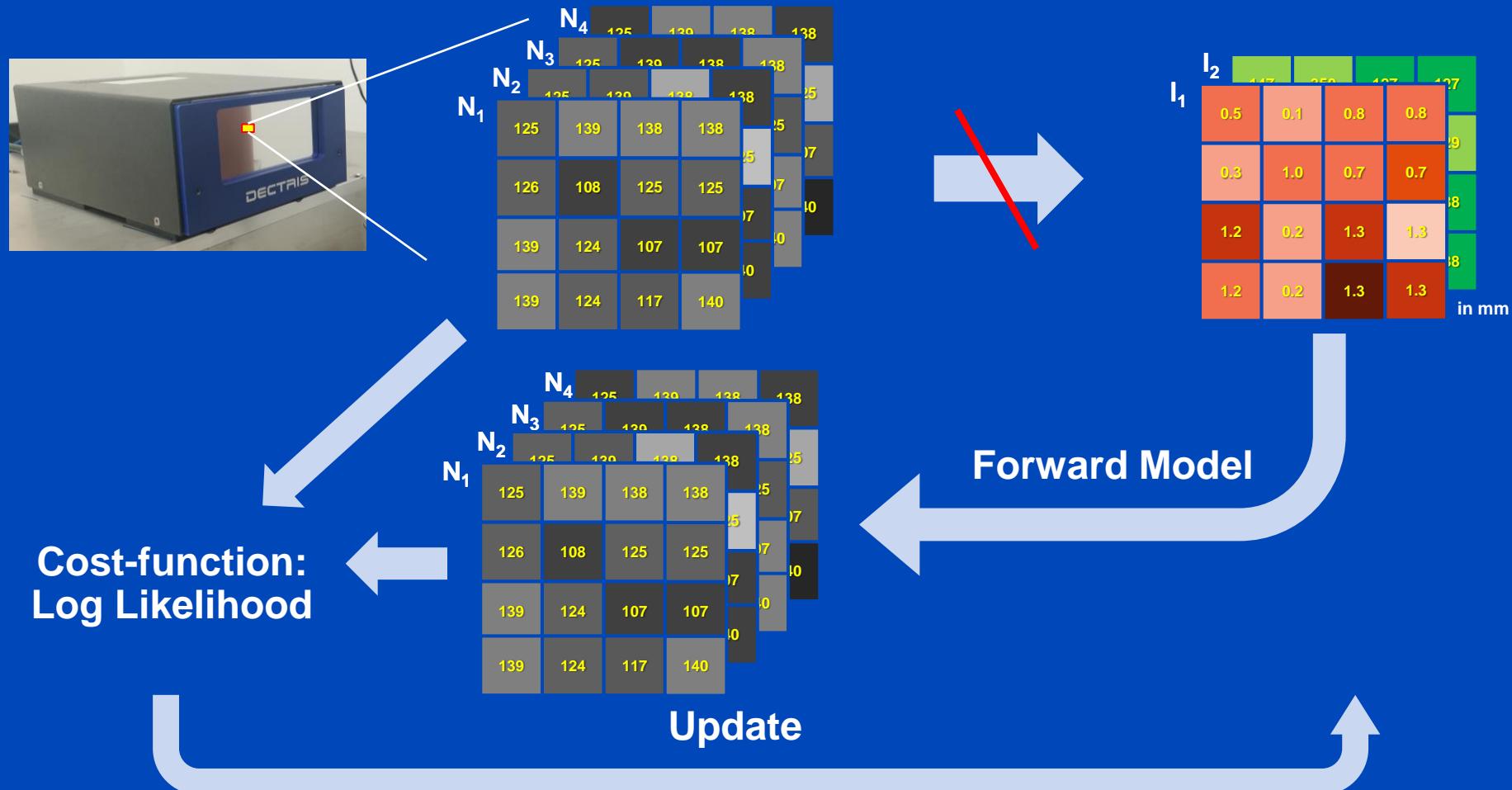
150 x 150 μm^2

Sensor thickness

1.0 mm CdTe

Material Decomposition

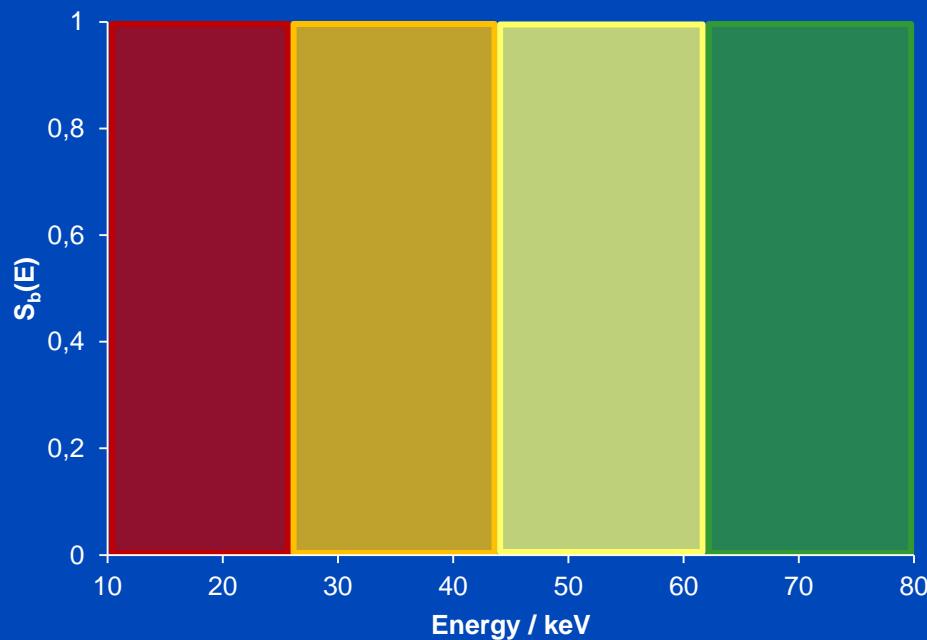
$$N_b(l_{1,\dots,M}) \propto N_{0,b} \int dE \ w(E) \cdot S_b(E) \cdot \exp \left(- \sum_{m=1}^M \mu_m(E) \cdot l_m \right)$$



Material Decomposition

- The detection process of a PCD is described using the bin sensitivity function $S_b(E)$.

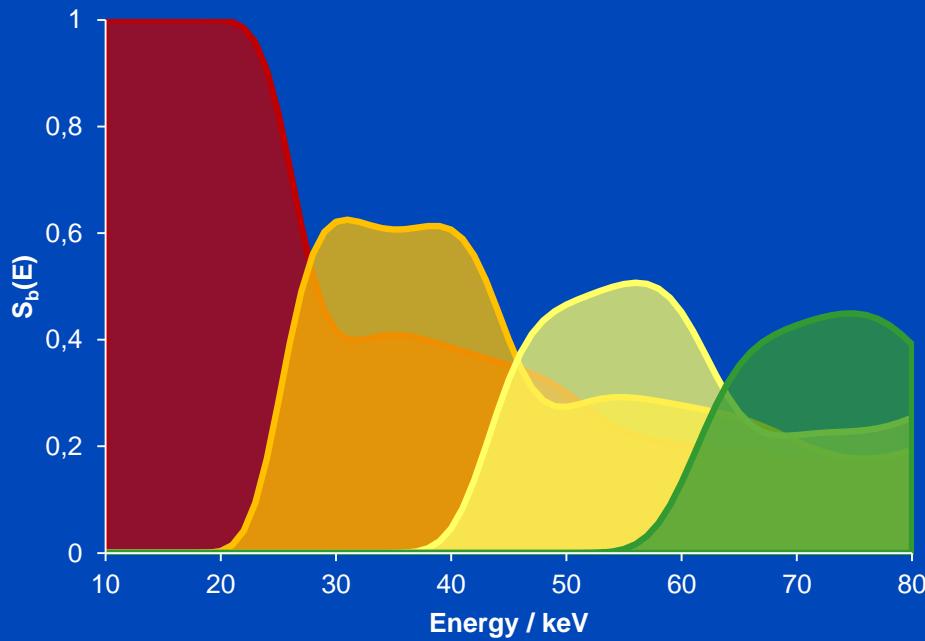
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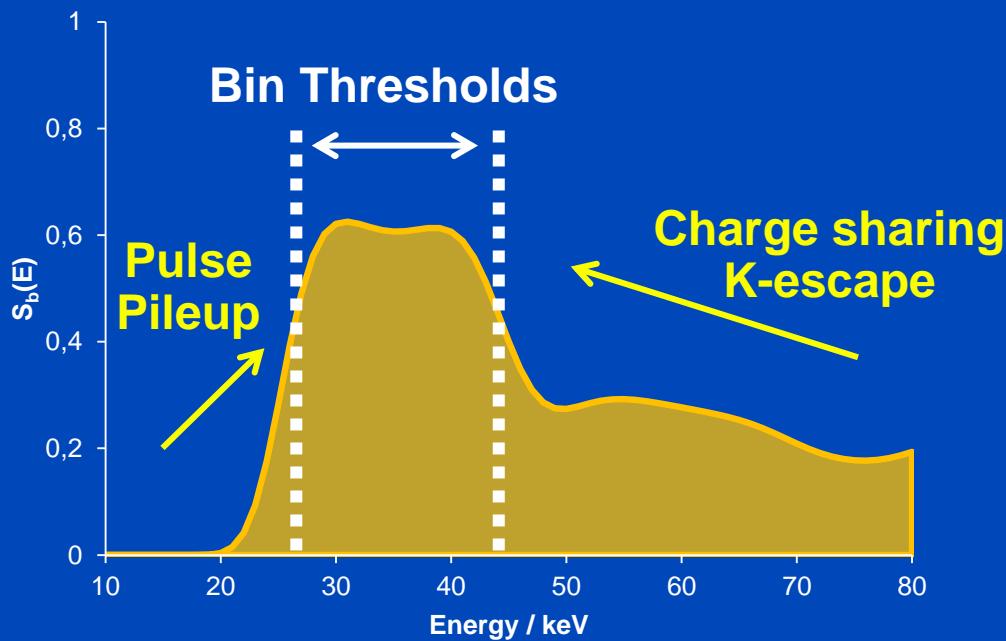
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Material Decomposition

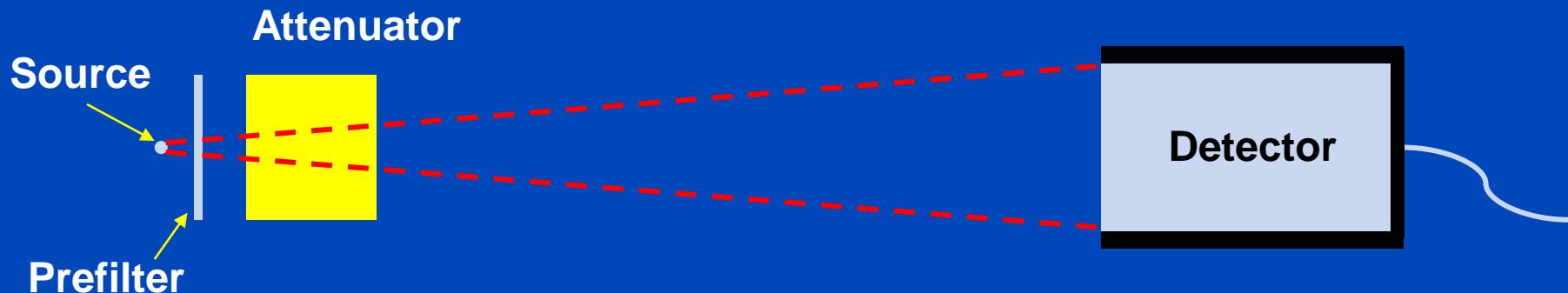
- The detection process of a PCD is described using the bin sensitivity function $S_b(E)$.

$$N_b(l_1, \dots, M) \propto N_{0,b} \int dE \ w(E) \cdot S_b(E) \cdot \exp \left(-\sum_{m=1}^M \mu_m(E) \cdot l_m \right)$$



Calibration Measurements

- Measure **transmission** through slabs of aluminum and POM
- Adapt forward model for each patch of 10x10 pixels such that it reproduces the calibration measurement



Reference Methods

- **Method 1 by Liu et al. (2015)**

$$N_b(l_{1,\dots,M}) \propto N_{0,b} \cdot C_b \left(\int dE \ w(E) \cdot S_b(E) \cdot \exp \left(- \sum_{m=1}^M \mu_m(E) \cdot l_m \right) \right)$$
$$C_b(N) = \frac{\alpha_b + \beta_b \cdot N}{1 + \gamma_b \cdot N}$$

- **Method 2 by Sidky et al. (2005)**

$$N_b(l_{1,\dots,M}) \propto N_{0,b} \cdot \int dE \underbrace{w_b(E) \cdot S_b(E)}_{=w_b(E)} \cdot \exp \left(- \sum_{m=1}^M \mu_m(E) \cdot l_m \right)$$

Liu, et al. (2015) “Spectral response model for a multibin photon-counting spectral computed tomography detector and its applications”. *Journal of Medical Imaging*, 33502

Sidky et al. (2005) “A robust method of x-ray source spectrum estimation from transmission measurements: Demonstrated on computer simulated, scatter-free transmission data”. *Journal of Applied Physics*, 97(12), 124701.

Count Rate-Dependent Spectral Calibration

- Include a multiplicative correction function $P_b(E, N_b)$ to account for spectral distortions and effects depending on the count-rate N_b

$$N_b(l_{1,\dots,M}) \propto N_{0,b} \int dE \ w(E) \cdot S_b(E) \cdot P_b(E, N_b) \cdot \exp\left(-\sum_{m=1}^M \mu_m(E) \cdot l_m\right)$$

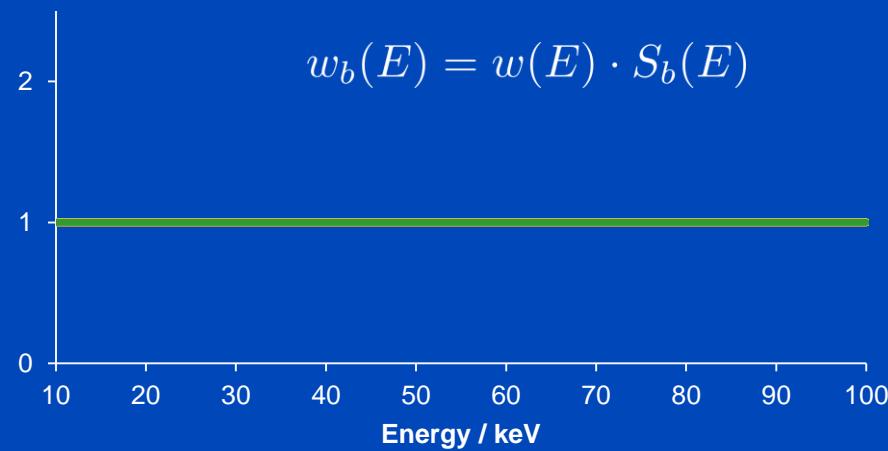
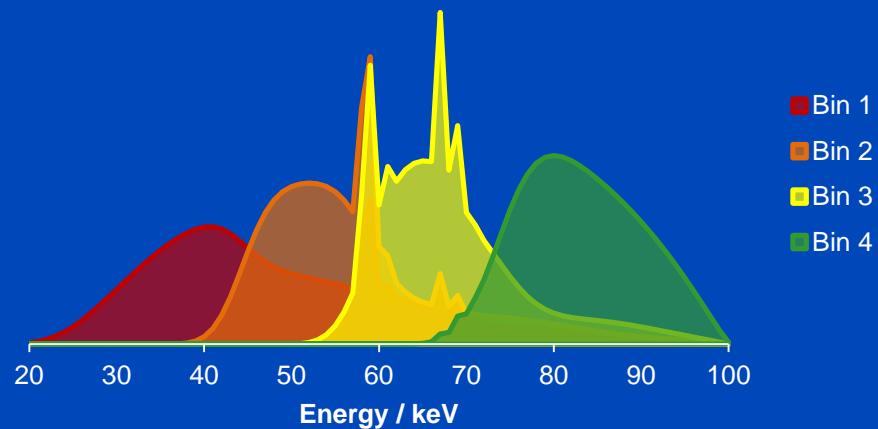
- Model the correction function as a polynomial of order K

$$P_b(E, N_b) = 1 + (E - E_{\min})(E - E_{\max}) \cdot \sum_{k=0}^{K-2} c_{kb}(N_b) E^k$$

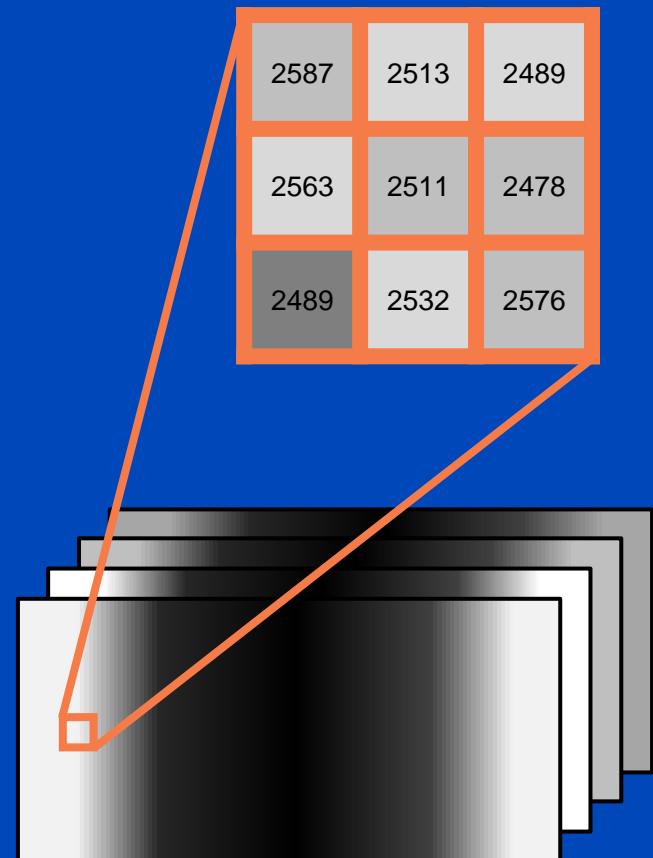
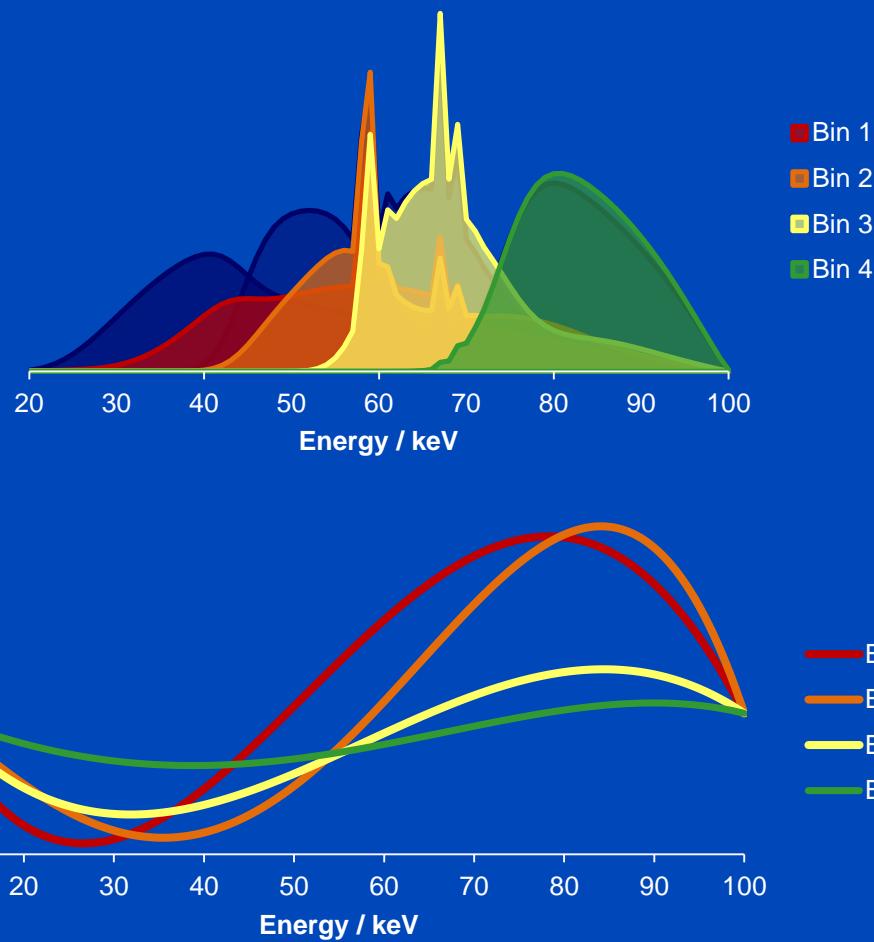
where the coefficients depend linearly on the count-rate

$$c_{kb}(N_b) = c_{kb}^{(0)} + c_{kb}^{(1)} \cdot N_b$$

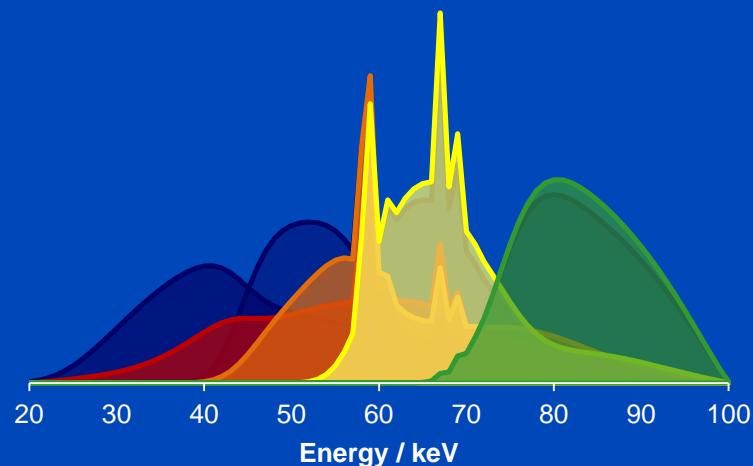
Count Rate-Dependent Spectral Calibration



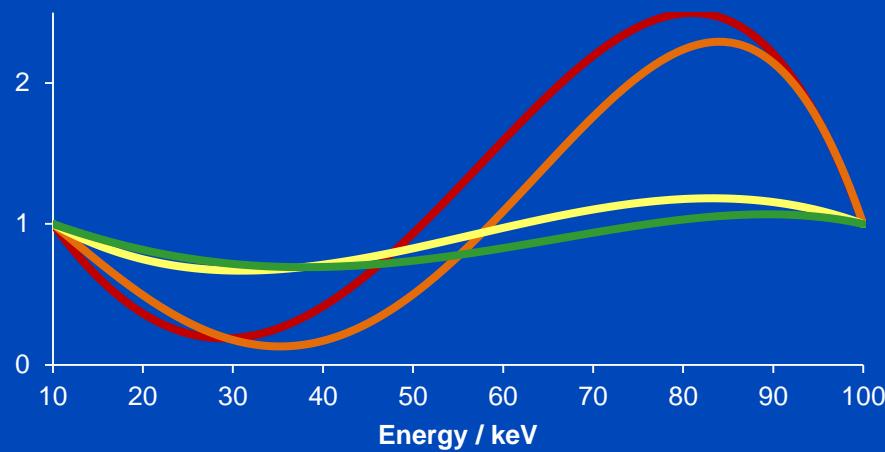
Count Rate-Dependent Spectral Calibration



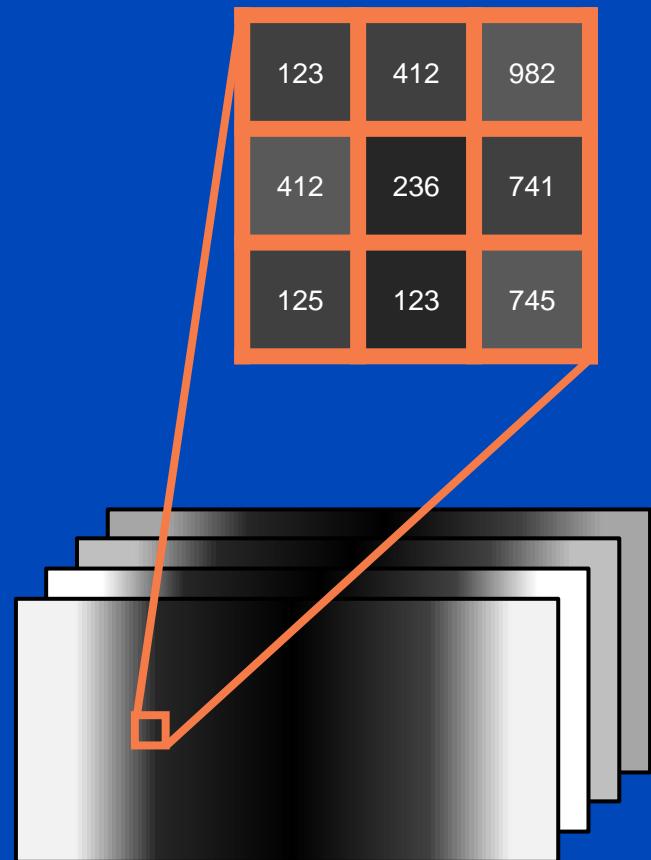
Count Rate-Dependent Spectral Calibration



- Bin 1
- Bin 2
- Bin 3
- Bin 4

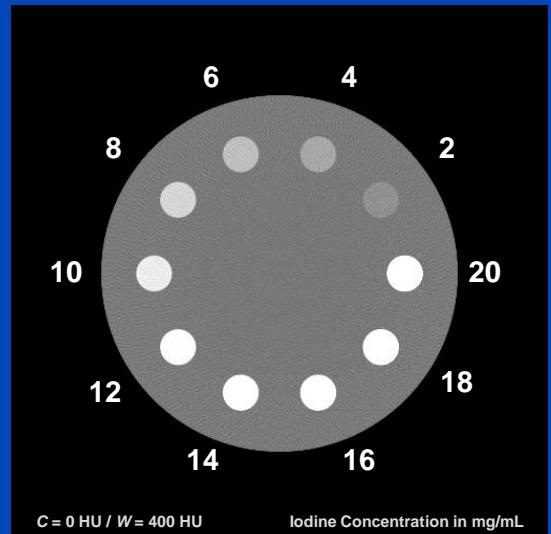


- Bin 1
- Bin 2
- Bin 3
- Bin 4



Simulation Study

- Material decomposition into iodine and water
 - Spectrum 80 kV, 6 mm Al prefiltration
- a) Distorted bin sensitivity function for decomposition
 - b) Simulated pulse pileup for paralyzable detector and rectangular shaped pulses



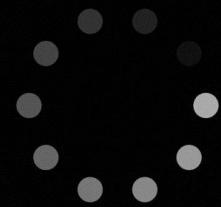
Faby et. al. (2016). “An efficient computational approach to model statistical correlations in photon counting x-ray detectors”. *Medical Physics*, 43(7), 3945–3960

Schlomka et. al. (2008) “Experimental feasibility of multi-energy photon-counting K-edge imaging in pre-clinical computed tomography” *Physics in Medicine and Biology*, 53(15), 4031–4047

Frey et. al. (2007). “Investigation of the use of photon counting x-ray detectors with energy discrimination capability for material decomposition in micro-computed tomography”. *Proceedings of SPIE Medical Imaging*, 65100A

Simulation Study

Ground Truth



Ref. 1

Ref. 2

Iodine Image
(Difference to
ground truth)

Prop.
Meth.

No pulse pileup

ideal

distorted

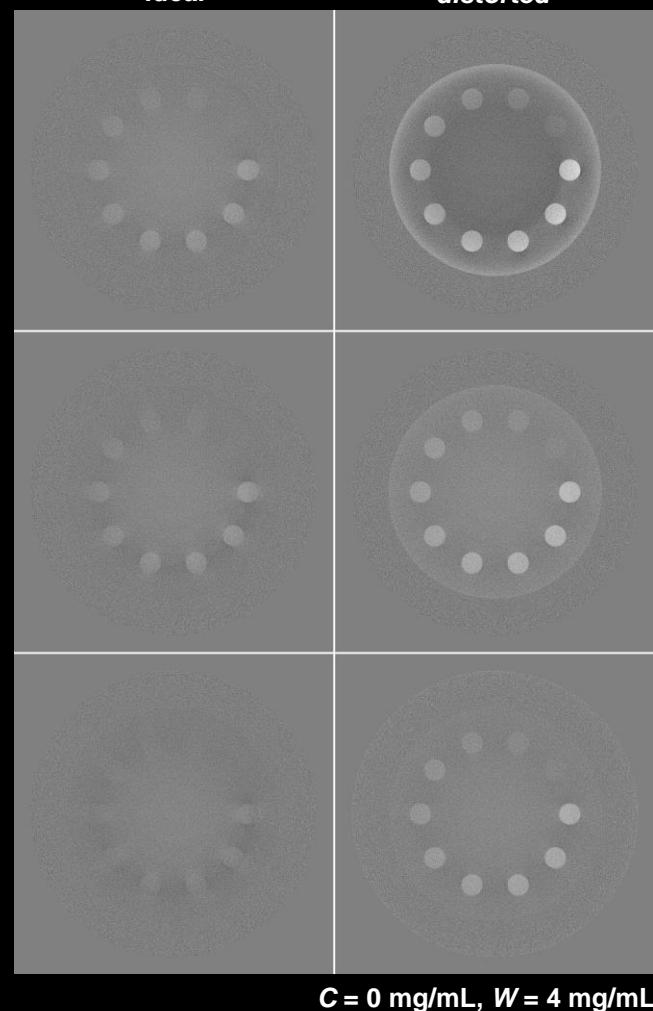
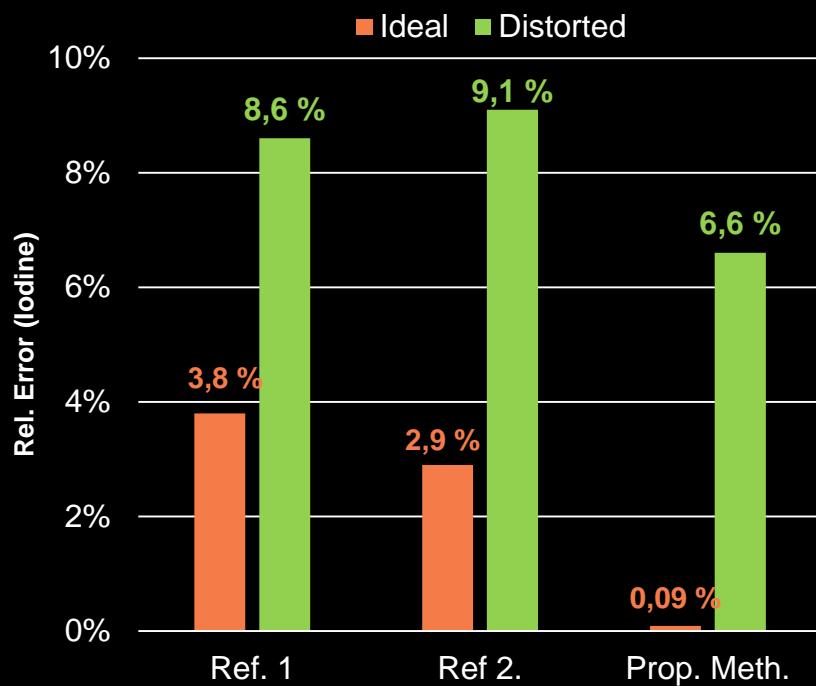
With pulse pileup

ideal

distorted

$C = 0 \text{ mg/mL}$, $W = 4 \text{ mg/mL}$

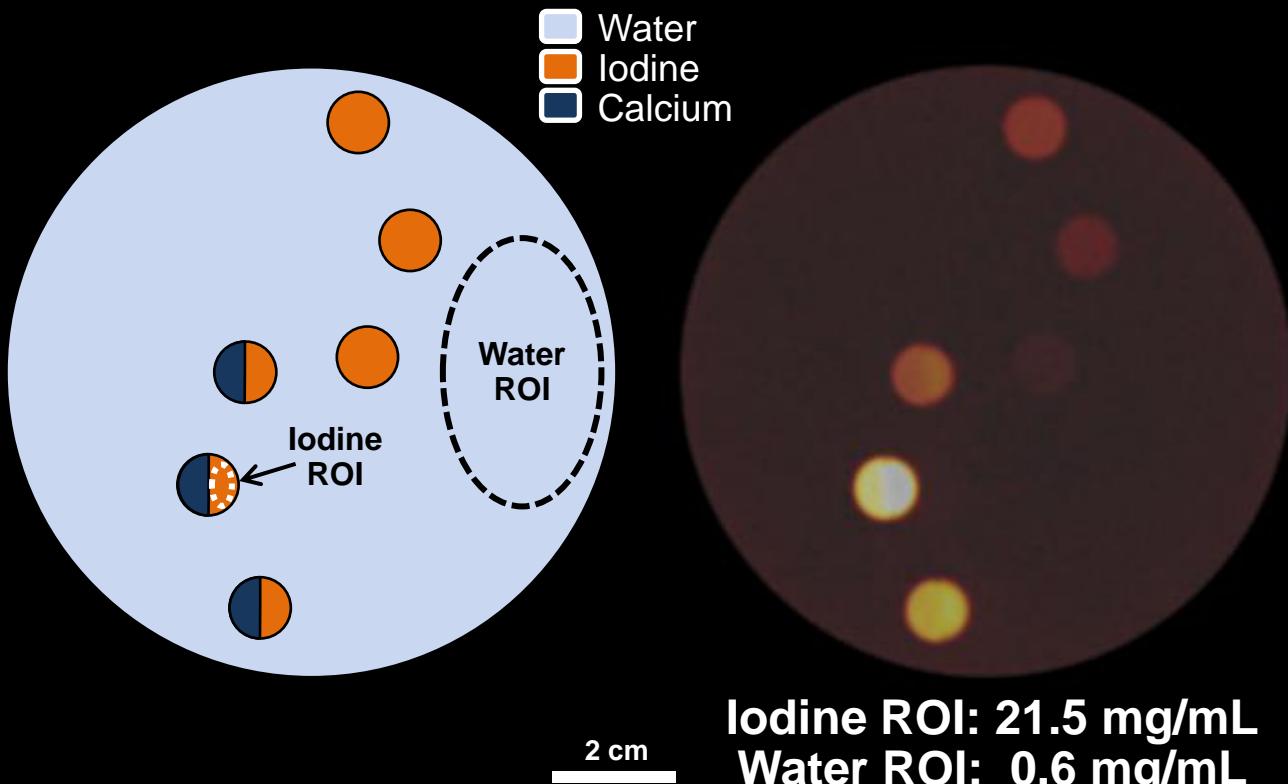
Simulation Study

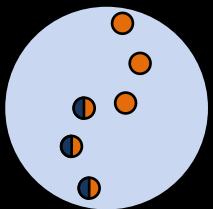


$C = 0 \text{ mg/mL}$, $W = 4 \text{ mg/mL}$

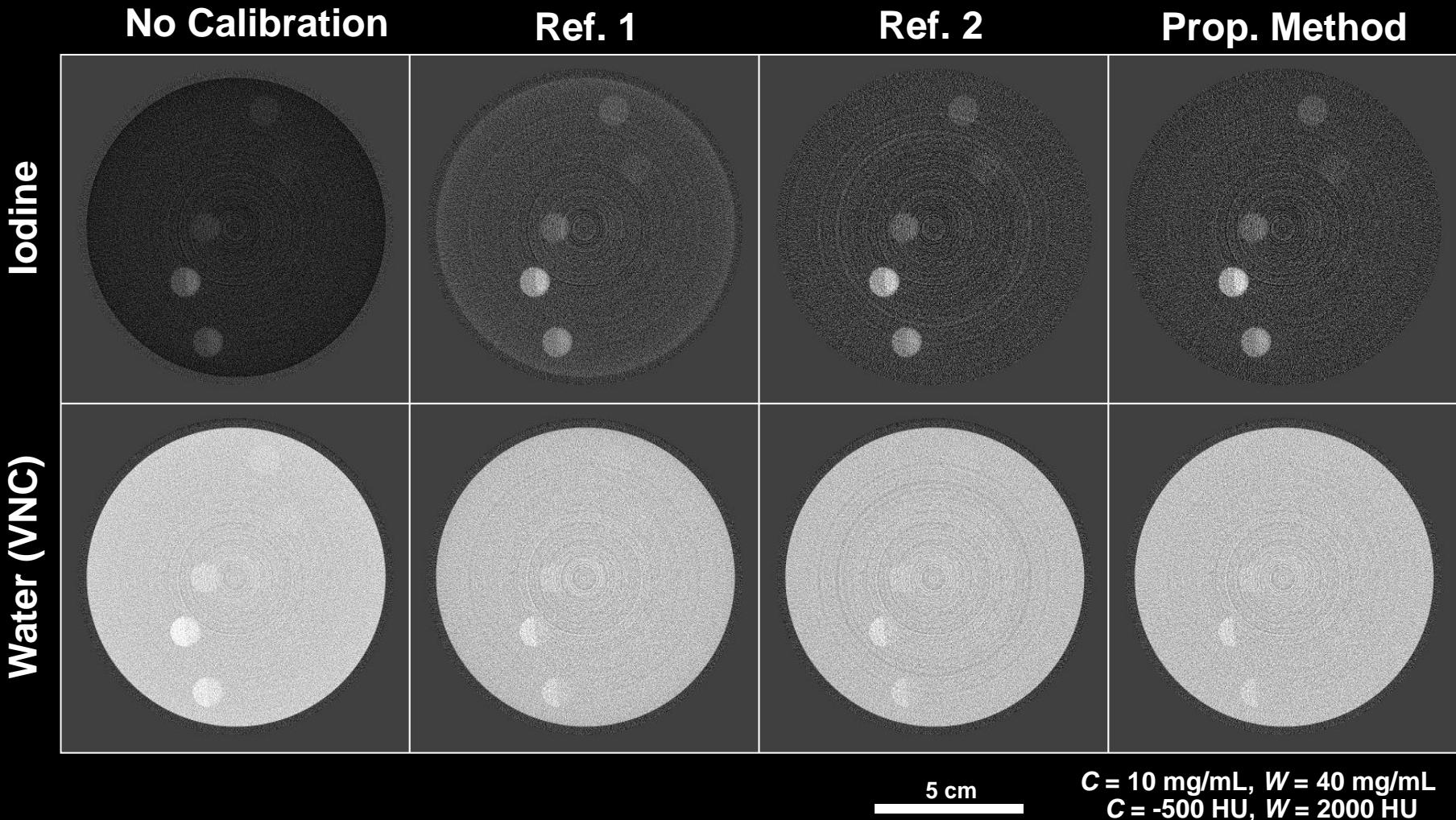
Phantom Measurements

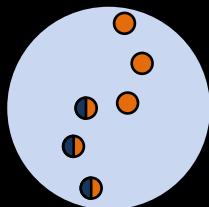
- QRM dual energy phantom DEP-002.
- Reference concentration determined with Siemens Somatom Definition Flash scanner.





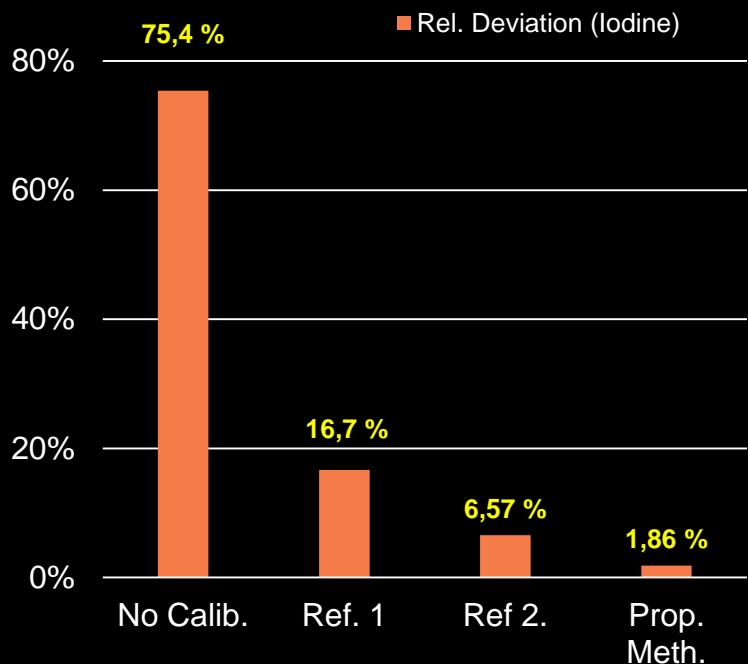
Phantom Measurements



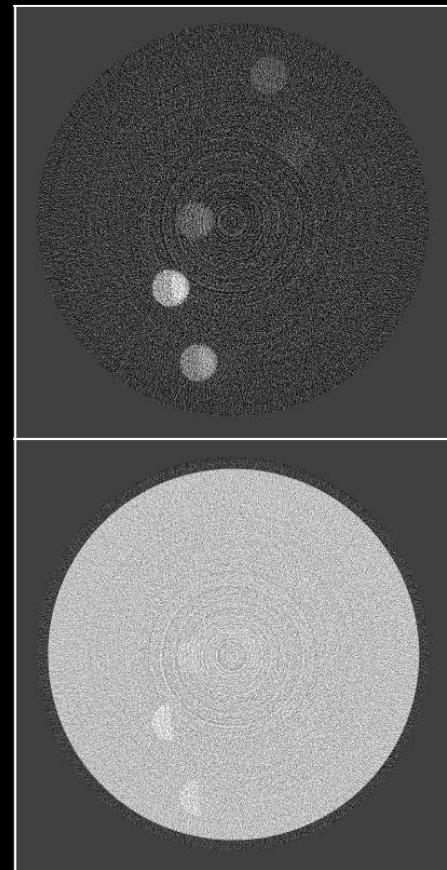


Phantom Measurements

Deviation from Reference Scan



Prop. Method



5 cm

$C = 10 \text{ mg/mL}$, $W = 40 \text{ mg/mL}$
 $C = -500 \text{ HU}$, $W = 2000 \text{ HU}$

Conclusions

- The **count rate-dependent spectral calibration** can accommodate both for spectral distortions and count rate-dependent effects.
- Not only **pulse pileup** is count rate-dependent, also effects like scatter correlate with the local count rate.
- In measurements, **artifacts** in material images were down to noise level.
- Agreement with clinical CT system within 2% for **iodine quantification**.

Thank You!

This presentation will soon be available at www.dkfz.de/ct.

The high-speed image reconstruction software
RayConStruct®-IR was provided by RayConStruct GmbH,
Nürnberg, Germany.

The prototype photon-counting x-ray detectors were
provided by Dectris Ltd., Baden, Switzerland.